

MOSFET ELECTRICAL CHARACTERISTICS						
Static Electrical Characteristics (Ta = 25 °C Unless Otherwise Noted)						
Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Static						
Drain-source breakdown voltage	V(BR)DSS	VGS = 0V, ID =-250μA	-20			V
Gate-source threshold voltage	VGS(th)	VDS =VGS, ID =-250μA	-0.5		-1	V
Gate-source leakage	IGSS	VDS =0V, VGS =±16V			±100	nA
Zero gate voltage drain current	IDSS	VDS =-20V, VGS =0V			-1	μA
Drain-source on-state resistancea	RDS(on)	VGS =-4.5V, ID = -3.2A		43	65	mΩ
		VGS =-2.5V, ID =-2A		56	90	mΩ
Forward transconductancea	gfs	VDS =-4.5V, ID =-4A		4		S
Diode forward voltage	VSD	IS=-1.25A,VGS=0V			-1.3	V
Dynamic						
Input capacitance	Ciss	VDS =-10V,VGS =0V, f=1MHz		415		pF
Output capacitance	Coss			223		pF
Reverse transfer capacitanceb	Crss			87		pF
Total gate charge	Qg	VDS =-10V,VGS =-4.5V, ID =-4.5A		24	36	nC
Gate-source charge	Qgs			18		nC
Gate-drain charge	Qgd			2.7		nC
Gate resistance	Rg	f=1MHz		6.0		Ω
Switchingb						
Turn-on delay time	td(on)	VDD=-10V RL=10Ω, ID ≈-1A, VGEN=-4.5V,Rg=6Ω		22	35	ns
Rise time	tr			35	60	ns
Turn-off delay time	td(off)			45	70	ns
Fall time	tf			25	40	ns
Drain-source body diode characteristics						
Continuous Source-Drain Diode Current	IS	Tc=25°C			-1.3	A
Pulsed Diode forward Curren	ISM				-20	A
Note :						
1. Repetitive Rating : Pulse width limited by maximum junction temperature.						
2. Surface Mounted on FR4 Board, t < 5 sec.						
3. Pulse Test : Pulse Width≤300μs, Duty Cycle ≤ 2%.						
4. Guaranteed by design, not subject to production testing.						

TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

